



Date Created: 1/19/2004
Date Issued: 2/3/2004
PCN # 20040303

FORECAST CHANGE NOTIFICATION

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence. This is a preliminary notification. A final PCN will be issued when qualification is complete and data is available.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

If you have any questions concerning this change, please contact:

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PCN Originator

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REL Engineer

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PCN Type: Alternate Assembly/Test Location/Qualification

Effectivity

Expected 1st Device Shipment Date: 5/10/2004
Earliest Year/Work Week of Changed Product: 0420
(Note: Package marking may differ from this format)

Product ID (Description):

Affects ANALOG devices in the T0220/263 -5lds packages. See FSID list below for a detailed list of devices affected.

Description of Change:

Fairchild Semiconductor intends to qualify Fairchild Cebu, Philippines facility as additional assembly site to build Analog T0220/263 -5lds packages. This will provide Fairchild Semiconductor the ability to respond quickly to customer demand for these products with additional flexibility in manufacturing locations. These products are currently produced in the assembly and test facility of our subcontractor in Enoch, South Korea.

Effect of Change:

The product test conditions limit and performance will remain unchanged.

Qualification:

The qualification plan as written is intended to meet all the criteria for qualifying assembly and test location and the overall reliability of the product.

Qual/REL Plan Numbers

Additional Qualification Data

Qual/REL Plan Numbers

Qual Plan: Q20030094

From: GMARCUS Date: 5/1/2004 Qual Plan: Q20030094
Requestor of Qualification: Yun Chow

Device: FAN1581T
Product Line: Analog

Qualification Stress Test and Sample Size Detail

DeviceA:	FAN1581T
Package:	TT220/263
# Leads:	005

Environmental Stress Detail:

Stress	P/C	Standard	Conditions	Readpoints			Sample		
				TP1	TP2	TP3	A	B	C
ACLV	X		100%RH, 121C	96			77	77	77
HAST1	X		85%RH, 130C, 0V	48	96		77	45	45
HTSL			150C	168	500	1000	77	77	77
TMCL1	X		-65C, 150C	100	500		77	77	77

WLR/ALR Stress Detail:

Stress	P/C	Standard	Conditions	Readpoints	Sample		
				TP1	A	B	C
BPULL				1	5	5	5
BSHR				1	5	5	5
DSHR				1	5	5	5

Affected FSIDs

FAN1581MX
FAN1582MX

FAN1581T

FAN1582M25X